

# ISO 5618-1:2023-11 (E)

## Fine ceramics (advanced ceramics, advanced technical ceramics) - Test method for GaN crystal surface defects - Part 1: Classification of defects

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<b>Contents</b>		<b>Page</b>
Foreword .....		iv
Introduction .....		v
1	<b>Scope .....</b>	<b>1</b>
2	<b>Normative references .....</b>	<b>1</b>
3	<b>Terms and definitions .....</b>	<b>1</b>
4	<b>Classification of defects .....</b>	<b>3</b>
4.1	<b>General .....</b>	<b>3</b>
4.2	<b>Description of the defect classes .....</b>	<b>3</b>
4.2.1	<b>Dislocation .....</b>	<b>3</b>
4.2.2	<b>Process-induced defects .....</b>	<b>5</b>
	<b>Bibliography .....</b>	<b>7</b>